

NO: SAMM 684

Page: 1 of 2

LABORATORY LOCATION:
(PERMANENT LABORATORY)

MIMOS FAILURE ANALYSIS LABORATORY
MIMOS BERHAD
TECHNOLOGY PARK MALAYSIA
57000 KUALA LUMPUR
MALAYSIA

FIELD OF TESTING: **MECHANICAL**

This laboratory has demonstrated its technical competence to operate in accordance with MS ISO/IEC 17025:2017 (ISO/IEC 17025:2017).

This laboratory's fulfillment of the requirements of ISO/IEC 17025 means the laboratory meets both the technical competence requirements and management system requirements that are necessary for it to consistently deliver technically valid test results and calibrations. The management system requirements in ISO/IEC 17025 are written in language relevant to laboratory operations and operate generally in accordance with the principles of ISO 9001 (see Joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF TESTING: **MECHANICAL**

Materials/ Products Tested	Type of Test/ Properties Measured/ Range of Measurement	Standard Test Methods/ Equipment/Techniques
Wafer, IC Package and Electronic Component	Qualitative Elemental Analysis	In house procedure M3AASWIS 00049 with reference to ASTM E1508-12a (Reapproved 2019) (Qualitative measurement only)
		Field Emission Scanning Electron Microscope (FESEM) - Energy Dispersive X-ray Spectroscopy (EDS)
		In house procedure M3AASWIS 00048 with reference to ASTM E1508-12a (Reapproved 2019) (Qualitative measurement only)
		Dual Beam - Energy Dispersive X- ray Spectroscopy (EDS)

Signatories:

1. **Bazura Abdul Rahim**
2. **Siti Rahmah Esa**
3. **Hasniza Hashim**

NO: SAMM 684

Page: 2 of 2

SCOPE OF TESTING: MECHANICAL

Materials/ Products Tested	Type of Test/ Properties Measured/ Range of Measurement	Standard Test Methods/ Equipment/Techniques
<ul style="list-style-type: none"> • Solid • Solid suspended in liquid 	Physical/dimensional measurement in micro and Nano scale <ul style="list-style-type: none"> • Particle Size • Spacing 	ISO 13322-1: 2014 Equipment: <ul style="list-style-type: none"> • Transmission Electron Microscope (TEM) FEI TECNAI G2 F20 • Field Emission Scanning Electron Microscope (FESEM) HITACHI SU8030

Signatories:

1. **Bazura Abdul Rahim**
2. **Siti Rahmah Esa**
3. **Hasniza Hashim**
4. **Harnisah Tajudin**